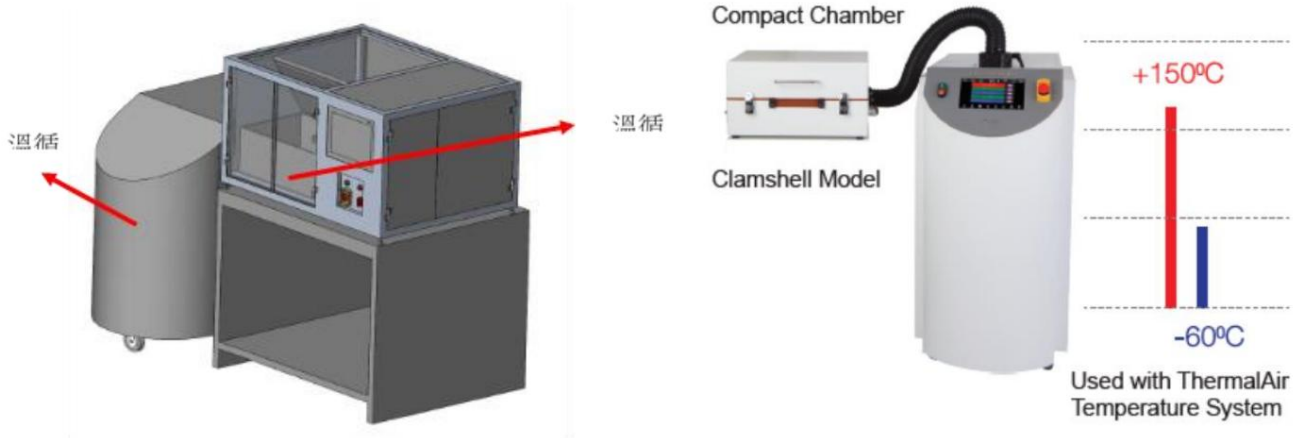
LIV high and low disk testing machine

Plate LIV H/L temperature Tester

Model number: TWC-LDTT-502



characteristic

ÿ Temperature test range: -45ÿ~100ÿ. ÿ

Temperature rise and

fall time: ÿ 25ÿ to -40ÿ: about 20 minutes.

ÿ 25ÿ to 100ÿ: about 20 minutes.

ÿ Applicable products: Optical communication

LD TO56. ÿ Test board capacity: 64 channels. (Can be customized

according to customer needs) ÿ Test method: X, Y-

axis slide automatic test ÿ Test function: LIV (Ith, Iop, Vop, Pop , Kink, Im, Id...) , SMSR, WL (When OSA) (the wavelength test part is optional

Equipped with OSA Anritsu9740A MM function) ÿ Test range

and accuracy:

• Allowable wavelength range: 1100nm ~ 1700nm. • LD

current (If, DAC): Range 0~500mA, Resolution 0.1mA, step 0.1mA minimum, accuracy 1mA

±0.5%.

• LD voltage(Vf, ADC): Range 0~5V, Resolution 0.01V, Accuracy 2%, Full scale. • Vbias_LD(DAC): Range

0~5V, Resolution 0.01V, Accuracy ±0.5%, Full scale. • LD dark current (Id_LD, ADC): Range 0~100uA,

Resolution 0.1uA, Accuracy 1%, Full scale. • Vbias_PD(DAC): Range 0~5V, Resolution 0.01V, Accuracy ±0.5%, Full scale . •

PD current(Im, ADC): Range 0~2000uA, Resolution 0.1uA, Accuracy ±1%, Full scale. • PD dark

current(Id_PD, ADC): Range 0~250nA, Resolution 0.1nA, Accuracy 3nA ±1%, Full scale. • Power detector (Pf, ADC):

Range depends on different attenuators, Resolution 0.001mW, Stability 2% (must be verified with fixed light source), Full scale.

• Wavelength test: 650nm~1750nm, Resolution: ÿ0.1nm.

ÿ Cycle Time: ÿ 3sec. (LIV measurement of 200 points, ex.0~100mA step=0.5mA) ÿ Cycle Time: ÿ 6sec. (LIV+SMSR+WL/Load-unLoad)

Specification

ÿ Voltage: One-way 220V/60Hz. ÿ

Appearance dimensions: 1200mm(W) x 1497mm(H) x 901mm(T). ÿ

Electric axis: •

Servo motor slide: 2 axes ÿ

Manual XYZ-3-axis slide: 1 set ÿ

Foot switching mode: programmable Change the following pin positions.

